

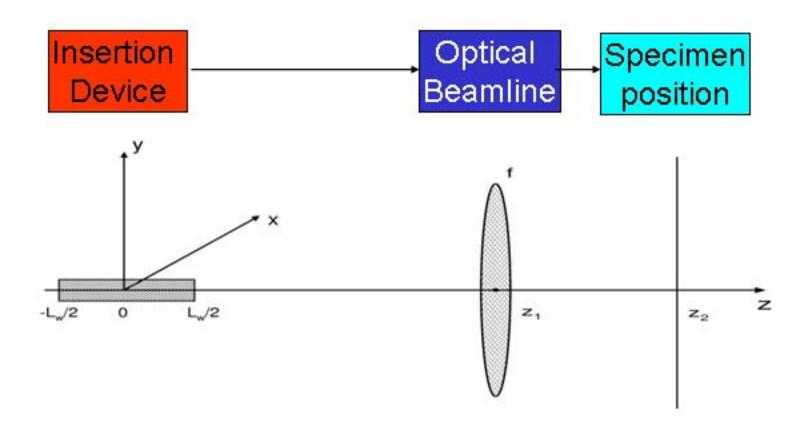
Statistical Optics and Partially Coherent X-ray Beams in Third Generation Light Sources

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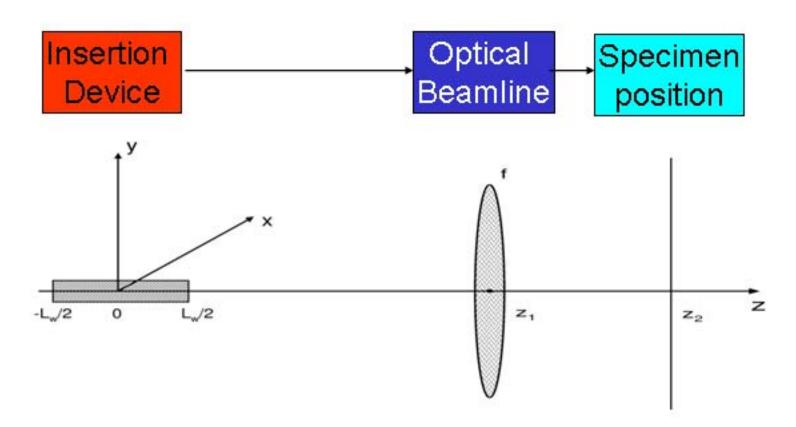
Deutsches Elektronen-Synchrotron DESY, Hamburg

DESY 05-032 - DESY 05-109 - DESY 06-037









$$\left| \Gamma_{\omega}(z_{o}, \vec{r}_{\perp o1}, \vec{r}_{\perp o2}, \omega, \omega') = \left\langle \overline{E}(z_{o}, \vec{r}_{\perp o1}, \omega) \overline{E}^{*}(z_{o}, \vec{r}_{\perp o2}, \omega') \right\rangle$$



Assumptions:

 $\checkmark \lambda << \sigma_b, \sigma_b$ bunch length

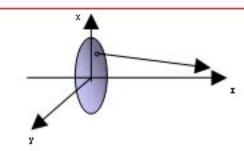
$$\checkmark \Delta \omega_{\text{undu}} >> c I \sigma_{\text{b}}$$

$$\Gamma_{\omega}(z_o, \vec{r}_{\perp o1}, \vec{r}_{\perp o2}, \omega, \omega') = NF_{\omega}(\omega - \omega')G_{\omega}(z_o, \vec{r}_{\perp o1}, \vec{r}_{\perp o2}, \omega)$$

Cross-spectral density

$$G_{\omega}(z_o, ec{r}_{\perp o1}, ec{r}_{\perp o2}, \omega) = \left\langle ar{E}_{s\perp}(ec{\eta}, ec{l}, z_o, ec{r}_{\perp o1}, \omega) ar{E}_{s\perp}^*(ec{\eta}, ec{l}, z_o, ec{r}_{\perp o2}, \omega)
ight
angle_{ec{\eta}, ec{l}}$$

Random variables: e- angle η +offset ι





STATISTICAL OPTICS

1) Source characterization

Tracking of the radiation through optical elements

Source characterization

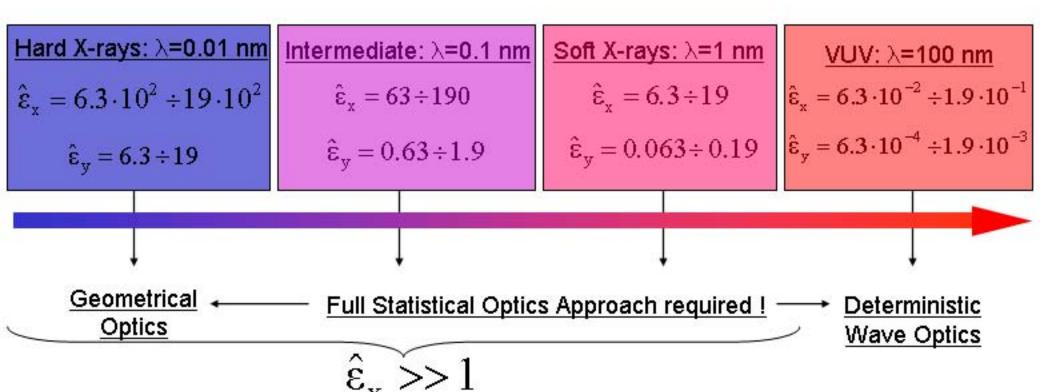


$$\epsilon_{x} = 1 \div 3 \text{ nmrad}$$

$$\epsilon_{y} = 0.01 \div 0.03 \text{ nmrad}$$

$$\lambda = 10^{-2} \div 10^{2} \text{ nm}$$

$$\hat{\epsilon} = \frac{2\pi \epsilon}{\lambda}$$



Source characterization



Source characterization

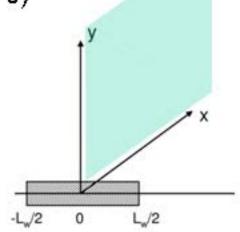
Cross-spectral density G at a certain z in free space + Maxwell Equations → source characterized

but useful to describe the source through a VIRTUAL SOURCE

1) located at position of minimal betatron functions (z=0)

2) at any distance: same field as undulator

Virtual source is characterized when G at z=0 is given

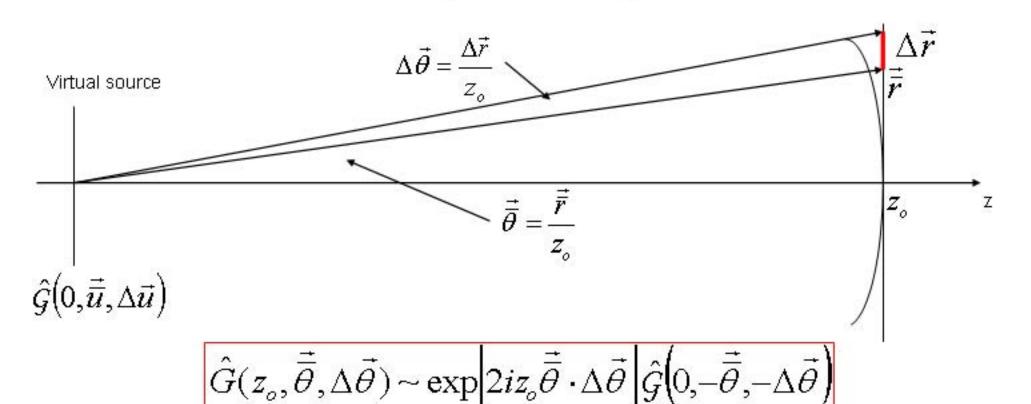


Source characterization: the importance of the far zone



Fourier Optics offers relation between G in the far zone and at the virtual source

$$\hat{G}\left(z, \vec{\overline{u}}, \Delta \vec{u}\right) = \int d\vec{\overline{r}}' \, d\Delta \vec{r}' \, G(z, \vec{\overline{r}}', \Delta \vec{r}') \exp\left[2i(\vec{\overline{u}} \cdot \Delta \vec{r}' + \Delta \vec{u} \cdot \vec{\overline{r}}')\right]$$
$$\vec{r} = \frac{r_1 + r_2}{2} \qquad \Delta r = \frac{r_1 - r_2}{2}$$



Source characterization: undulator field in normalized units



$$G_{\omega}(z_o, ec{r}_{\perp o1}, ec{r}_{\perp o2}, \omega) = \left\langle ar{E}_{s\perp}(ec{\eta}, ec{l}, z_o, ec{r}_{\perp o1}, \omega) ar{E}_{s\perp}^*(ec{\eta}, ec{l}, z_o, ec{r}_{\perp o2}, \omega)
ight
angle_{ec{\eta}, ec{l}}$$

•Paraxial approximation:

 $L_f >> \lambda$ always applicable for SR

Resonance approximation:

N_w >> 1 freq. ~ fundamental freq.
$$\omega_o = \frac{4\pi c\gamma^2}{\lambda_w \left(1+K^2/2\right)}$$
 also non-restrictive

Source characterization: undulator field in normalized units



Use of normalized units:

$$\hat{z} = \frac{z}{L_w}$$
 $\vec{\hat{l}} = \vec{l}\sqrt{\frac{\omega}{L_w c}}$
 $\vec{\hat{\eta}} = \vec{\eta}\sqrt{\frac{\omega L_w}{c}}$
 $\hat{C} = L_w C = 2\pi N_w \frac{\omega - \omega_o}{\omega}$

Longitudinal length

Transverse length

All angles: transverse/longitudinal

Detuning from resonance

Source characterization: undulator field in normalized units



New variables; from
$$\vec{r}$$
 to $\vec{\theta} = \frac{\vec{r}}{z_o}$; then $\hat{\theta} = \vec{\theta} \sqrt{\frac{\omega L_w}{c}}$

$$\hat{E}_{\mathbf{s}\perp} = \exp(i\Phi_{\mathbf{u}}) \int_{-1/2}^{1/2} \frac{\hat{z}_o d\hat{z}'}{\hat{z}_o - \hat{z}'} \exp\left\{i \left[\hat{C}\hat{z}' + \frac{\hat{z}_o\hat{z}'}{2(\hat{z}_o - \hat{z}')} \left(\vec{\hat{\theta}} - \frac{\vec{\hat{l}}}{\hat{z}_o} - \vec{\hat{\eta}}\right)^2\right]\right\} \quad \Phi_{\mathcal{U}} = \left(\vec{\hat{\theta}} - \frac{\vec{\hat{l}}}{\hat{z}_o}\right)^2 \frac{\hat{z}_o}{2}$$

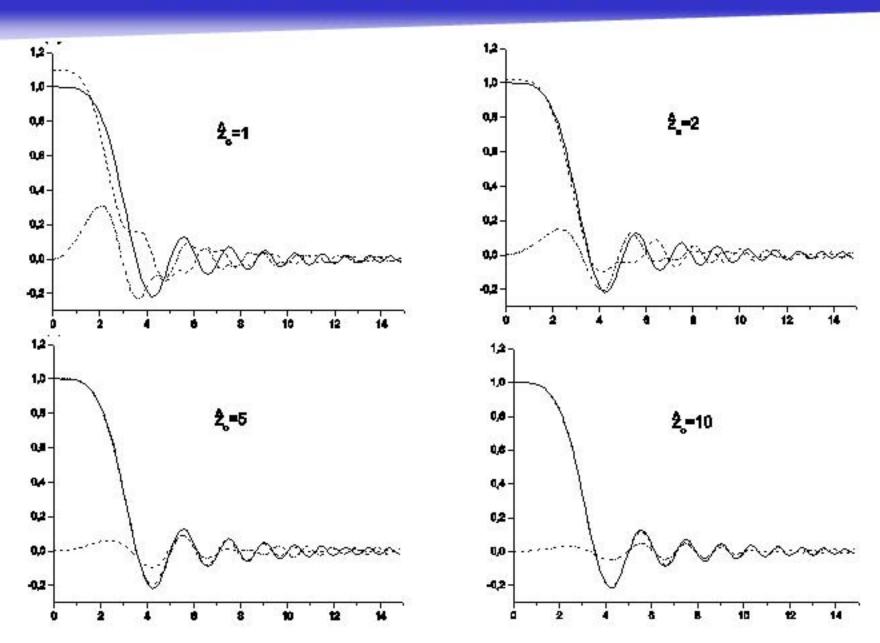
$$\hat{E}_{s\perp}\left(\hat{C},\hat{z}_{o},\hat{ ilde{ heta}}-rac{ec{\hat{l}}}{\hat{z}_{o}}-ec{\hat{\eta}}
ight)=\exp{(i\Phi_{U})S}\left[\hat{C},\hat{z}_{o},\left(ec{\hat{ heta}}-rac{ec{\hat{l}}}{\hat{z}_{o}}-ec{\hat{\eta}}
ight)^{2}
ight]$$

And when Ĉ=0 (perfect resonance)

$$S\left(0,\hat{z}_o,\zeta^2\right) = \exp(-i\hat{z}_o\zeta^2/2)\hat{z}_o\left[\operatorname{Ei}\left(\frac{i\hat{z}_o^2\zeta^2}{-1+2\hat{z}_o}\right) - \operatorname{Ei}\left(\frac{i\hat{z}_o^2\zeta^2}{1+2\hat{z}_o}\right)\right]$$

Source characterization: the undulator field





Source characterization: the cross-spectral density function



Angular coordinates:

$$\overline{\theta} = \frac{\hat{\theta_1} + \hat{\theta_2}}{2}$$

$$\overline{\theta} = \frac{\hat{\theta}_1 + \hat{\theta}_2}{2} \qquad \Delta \hat{\theta} = \frac{\hat{\theta}_1 - \hat{\theta}_2}{2}$$

The cross-spectral density function in free space at resonance (C=0)

$$\hat{G}(\overline{\theta}_x, \overline{\theta}_y, \Delta \hat{\theta}_x, \Delta \hat{\theta}_y; \hat{z}_o, \hat{N}_x, \hat{N}_y, \hat{D}_x, \hat{D}_y)$$

Main transverse parameters: $\hat{D}_{x,y} = \sigma_{x',y'}^2 \frac{\omega L_w}{c}$ $\hat{N}_{x,y} = \sigma_{x,y}^2 \frac{\omega}{cL_w}$

$$\hat{\varepsilon} = \frac{2\pi \,\varepsilon}{\lambda} = \sqrt{\hat{N}\hat{D}}$$

- Involves only 2 integrations
- still pretty generic
- useful for numerical techniques

Source characterization: cross-spectral density function



When $\hat{D}_x >> 1$ and $\hat{N}_x >> 1$ we obtain factorization of G:

$$\hat{G} = \hat{G}_x \hat{G}_y$$

In the far zone limit with $\hat{N}_x >> 1$, $\hat{D}_x >> 1$:

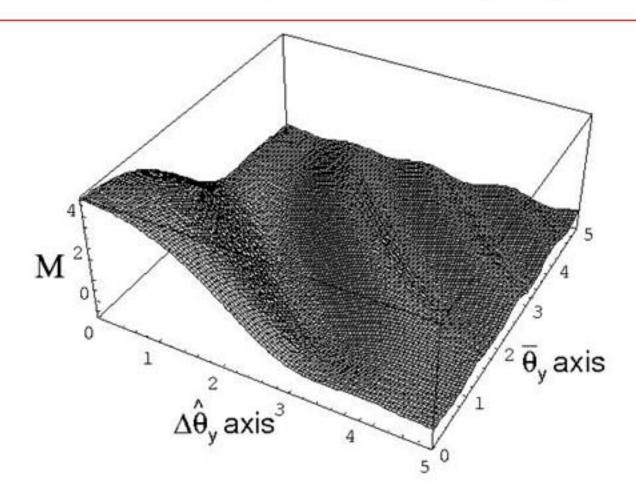
$$\hat{G}_{x} = \exp[i2\overline{\theta}_{x}\hat{z}_{o}\Delta\hat{\theta}_{x}] \exp[-2\hat{N}_{x}\Delta\hat{\theta}_{x}^{2}]$$

$$\hat{G}_{y} = \exp[i2\overline{\theta}_{y}\hat{z}_{o}\Delta\hat{\theta}_{y}] \exp[-2\hat{N}_{y}\Delta\hat{\theta}_{y}^{2}] \cdot \int_{-\infty}^{\infty} d\hat{\varphi}_{y} \exp\left[-\frac{\left(\overline{\theta}_{y} + \hat{\varphi}_{y}\right)^{2}}{2\hat{D}_{y}}\right] M(\hat{\varphi}_{y}, \Delta\hat{\theta}_{y})$$

Source characterization: the M function



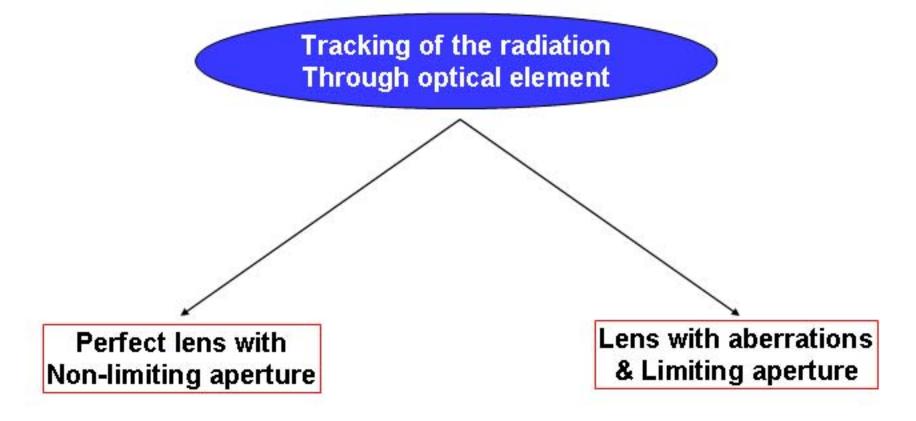
$$M(\bar{\theta}_y, \Delta \hat{\theta}_y) = \int_{-\infty}^{\infty} d\hat{\phi}_x \mathrm{sinc} \left[\frac{\hat{\phi}_x^2 + (\bar{\theta}_y - \Delta \hat{\theta}_y)^2}{4} \right] \mathrm{sinc} \left[\frac{\hat{\phi}_x^2 + (\bar{\theta}_y + \Delta \hat{\theta}_y)^2}{4} \right]$$



Tracking of G



$\hat{\mathbf{G}}$ in the far field $\rightarrow \hat{\mathcal{G}}\left(0, \vec{u}, \Delta \vec{u}\right) \leftrightarrow \hat{\mathcal{G}}\left(0, \vec{r}, \Delta \vec{r}\right)$



Tracking of G: perfect lens case



For perfect lenses results are immediate both at the focal and the image plane

At the focal plane we reproduce the F.T. of the cross spectral density at the source:

At the image plane we reproduce the cross spectral density at the source:

$$\hat{G}(\hat{z}_i, \vec{r}_i, \Delta \vec{r}_i) \sim \exp\left[\frac{2im}{\hat{z}_1}(1+m)\vec{r}_i \cdot \Delta \vec{r}_i\right] \hat{G}(0, -m\vec{r}_i, -m\Delta \vec{r}_i)$$

where
$$m = \frac{\hat{z}_1}{\hat{z}_2 - \hat{z}_1}$$

Tracking of G: non-perfect lens case



Limiting aperture+aberrations

In the most general case, at the image plane in the far field
the cross spectral density
is obtained convolving the cross spectral
density at the object plane (virtual source) with the
Amplitude point-spread function of the system:

$$\begin{split} \hat{G}_{P}(\hat{z}_{i},\vec{r}_{i},\Delta\vec{\hat{r}}_{i}) \; &= \; \mathrm{m} \exp \left[\frac{2i\mathrm{m}}{\hat{z}_{1}} \vec{r}_{i} \cdot \Delta\vec{\hat{r}}_{i} \right] \int d\vec{u} \; d\Delta\vec{u} \; \hat{G} \left(0, -\hat{z}_{1} \vec{u}, -\hat{z}_{1} \Delta\vec{u} \right) \; . \\ & \times \; \hat{\mathcal{P}} \left[\frac{\mathrm{m}}{\hat{z}_{1}} \left(\vec{r}_{i} + \Delta\vec{\hat{r}}_{i} \right) - \vec{u} - \Delta\vec{u} \right] \hat{\mathcal{P}}^{*} \left[\frac{\mathrm{m}}{\hat{z}_{1}} \left(\vec{r}_{i} - \Delta\vec{\hat{r}}_{i} \right) - \vec{u} + \Delta\vec{\hat{u}} \right] \end{split}$$

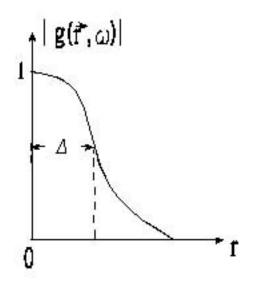
 $\hat{\mathcal{P}}$ is the F.T. of the pupil function

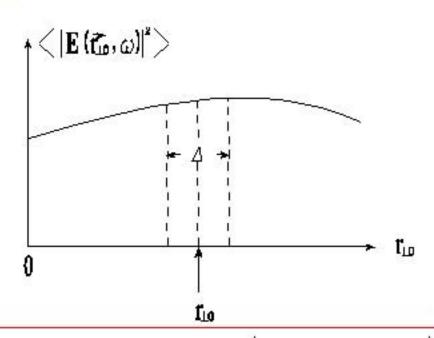
Source characterization



Particular kind of VIRTUAL SOURCE:

Quasi-homogeneous source

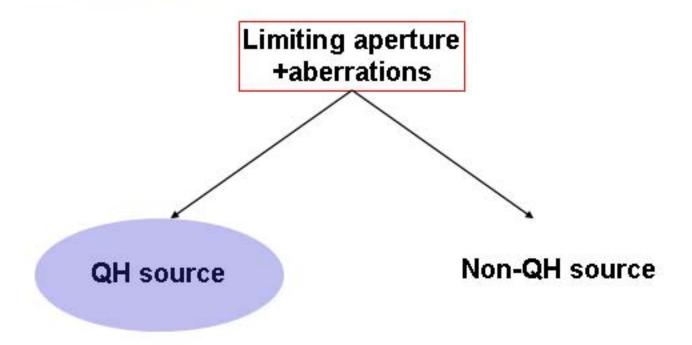




$$G = I(\vec{r}_{\perp 1}, \omega) g(\vec{r}_{\perp 2} - \vec{r}_{\perp 1}, \omega) \text{ where } I = \left\langle \left| \overline{E}(\vec{r}_{\perp 1}, \omega) \right|^2 \right\rangle$$

Tracking of G: non-perfect lens case





Simplification for the intensity at the image plane

Tracking of G: non-perfect lens case



Line spread function:

$$I_p = I_{ideal} * l$$

Diffraction effects are not important: the line spread function can be calculated with Geometrical Optics techniques

(ray tracing possible)

Diffraction effects are important: the line spread function can only be calculated with Physical Optics techniques

(no ray tracing possible)

Conclusions



- A theory describing spatial coherence from UR is proposed
- Step 1. Characterization of the source through cross-spectral density
 - FT of s.p. electric field from ID at any distance z_o, offset I + angle η
 - General expression found for G (5+1 parameters)
 - \hat{N}_x , $\hat{D}_x >> 1 \rightarrow \text{Separability } \hat{G} = \hat{G}_x \hat{G}_y$
 - G in the far zone allows characterization of virtual source
- Step 2. Tracking of G through the beamline
 - Case of perfect lens is immediate: focal and image plane
 - Non-perfect lens: convolve G with amplitude line spread function
 - Imaging. QH case → line spread function approach